

# Search Notes



Application/Control No.

10/517,066

Examiner

Sang Y. Paik

Applicant(s)/Patent under Reexamination

SATOU ET AL.

Art Unit

3742

## SEARCHED

Class	Subclass	Date	Examiner
219	470.1 472.1 472.12		
	477.1 460.1		
	477.11		
26	21R 21A		
	299R 299D 299E		
99	422 423		
	425 444		
	445		
411	203 204		
	205 206		
	207 212.1		
		7/21/05	2P

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
A3 ABOVE		7/21/05	2P

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
FAST EX SEARCHED	7/21/05	2P